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Autore	Maiti C. K
Titolo	Strain-engineered MOSFETs // C. K. Maiti, T. K. Maiti
Pubbl/distr/stampa	Boca Raton, : Taylor & Francis, c2013
ISBN	1-4665-0347-5
Edizione	[1st edition]
Descrizione fisica	1 online resource (311 p.)
Altri autori (Persone)	MaitiT. K
Disciplina	621.3815/284 621.3815284
Soggetti	Integrated circuits - Fault tolerance Metal oxide semiconductor field-effect transistors - Reliability Strains and stresses Electronic books.
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Front Cover; Contents; Preface; About the Authors; List of Abbreviations; List of Symbols; Chapter 1 - Introduction; Chapter 2 - Substrate-Induced Strain Engineering in CMOS Technology; Chapter 3 - Process-Induced Stress Engineering in CMOS Technology; Chapter 4 - Electronic Properties of Strain-Engineered Semiconductors; Chapter 5 - Strain-Engineered MOSFETs; Chapter 6 - Noise in Strain-Engineered Devices; Chapter 7 - Technology CAD of Strain-Engineered MOSFETs; Chapter 8 - Reliability and Degradation of Strain-Engineered MOSFETs Chapter 9 - Process Compact Modelling of Strain-Engineered MOSFETsChapter 10 - Process-Aware Design of Strain-Engineered MOSFETs; Chapter 11 - Conclusions; Back Cover
Sommario/riassunto	Currently strain engineering is the main technique used to enhance the performance of advanced silicon-based metal-oxide-semiconductor field-effect transistors (MOSFETs). Written from an engineering application standpoint, Strain-Engineered MOSFETs introduces promising strain techniques to fabricate strain-engineered MOSFETs and to methods to assess the applications of these techniques. The book provides the background and physical insight needed to understand new and future developments in the modeling and design of n- and p-MOSFETs at nanoscale. This book fo

2. Record Nr.	UNINA9910716823103321
Autore	Krenz Ronald D.
Titolo	Economics of large wheat farms in the Great Plains
Pubbl/distr/stampa	[Washington, D.C.] : , : Economic Research Service, United States Department of Agriculture, , 1974
Descrizione fisica	1 online resource (iii, 45 pages) : maps
Collana	Agricultural economic report ; ; no. 264
Soggetti	Wheat trade - Great Plains Wheat trade Great Plains
Lingua di pubblicazione	Inglese
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Livello bibliografico	Monografia
Note generali	"By Ronald D. Krenz, Walter G. Heid, Jr., and Harry Sitler"--Page 1. "July 1974."
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